S	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/550,349	VAN DER HEIJDEN, MARK
Examiner	Art Unit
Patricia T. Nguyen	2817

	SEARCHED			
Class	Subclass	Date	Examiner	
330	292	1/30/2008	PN	
	302			
	294			
	149			
			,	
,				

INTERFERENCE SEARCHED						
Clas	SS	Subclass	Da	te	Exan	niner
330)	292	1/30/2008		PN	
		302				
		294				
	14	49				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
		DATE	EXMR
EAST		1/30/2008	PN
	-		